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Transparent and conductive Pd-C nanostructural films

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INTRODUCTION

INTRODUCTION Transparent conducting films have been studied extensively because of their broad range of application such as transparent electrodes in display, in photovoltaic devices and optoelectronic systems. In this presentation we want to present carbonaceous -palladium films (C-Pd films) deposited on glassy or fused silica substrates. These films were obtained by two ways; first method was PVD process. Second method was PVD process followed by pyrolitic CVD process under influence of xylene. In PVD process two separated sources containing fullerenes and palladium acetate. In CVD process we were modifying C-Pd films prepared by PVD. Obtained films were characterized by SEM (topography) and morphology), AFM (topography) and adhesion, resistivity and by UV-VIS- FTIR absorption spectroscopy.



SEM images of PVD C-Pd film and CVD/PVD C-Pd film

AFM

	11.4 m	Standard Roughness		10/6	Standard Raughnes
	. Wannan Ma	Rax 1.66 nm Mpr 3.07 nm Mpr 3.05 nm Rt 9.66 nm Rt 7.14 nm		" man from	Rat 8.81 c Rps 71.82 c Rps 28.10 c Rt 08.86 c Rtv: 32.82 c
and the second second second	0 2000 4000 am			0 25 5µm	
	-Martin Malaur	Diandard Roughmess Rac 1.70 nm Rpc 7.32 nm Rpc 3.30 nm Rpc 3.30 nm Rt 14.20 nm Rtm 0.74 nm		10m	Standard Reughnes Pac 7.80 r Pp. 68.53 r Pperc 22.11 Pt. 135.8 r Ptr. 41.50 r
	184.00	Rented Prestress		142m	Standard Reactment
conductive	on the weather the	Par 1.52 rm Ppr 4.39 rm Ppr 3.39 rm Mt 10.92 rm Parc 0.22 rm	nonconductive	3 nh	Ra: 3.49 Rg: 35.59 Rpey: 11.11 Rt: 51.34 Ray: 21.24
	V1			v.	

Average roughness

Properties of prepared C-Pd films							
	Sample no	Pd content Wt %	C-Pd film resistivity [kOhm cm]	Film thickness [nm]			
	PVD1	16	18	300			
	PVD2	~10	nonconductive	300			
-	CVD/PVD1	-	14	» 400nm	V		
	CVD/PVD2	-	6000	>> 400nm			





